

±30V, 29A&-27A, 21mΩ&20mΩ N And P-channel Power Trench MOSFET

JMTG200C03D

Features

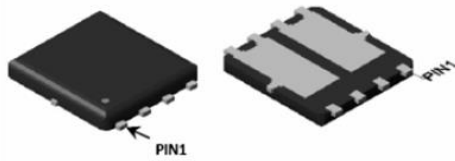
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS Tested
- 100% ΔV_{ds} Tested
- Halogen-free; RoHS-compliant

Applications

- Load Switch
- PWM Application
- Power Management

Product Summary

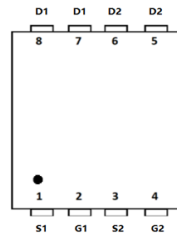
Parameters	N	P	Unit
V_{DSS}	30	-30	V
$V_{GS(th_Typ)}$	1.7	-1.7	V
$I_D(@V_{GS}=10V)$	29	-27	A
$R_{DS(ON)_Typ}(@V_{GS}=10V)$	15	15	mΩ
$R_{DS(ON)_Typ}(@V_{GS}=4.5V)$	21	20	mΩ



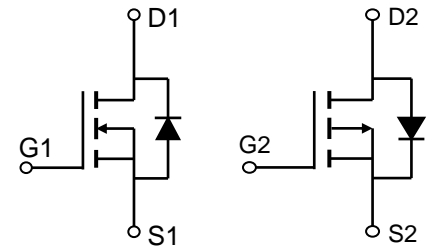
Top View

Bottom View

PDFN5X6-8L-D



Pin Assignment



Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMTG200C03D	G200C03D	1	Tape&Reel	PDFN5x6-8L-D	5000	50000

Absolute Maximum Ratings (@ $T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value-N	Value-P	Unit
V_{DS}	Drain-to-Source Voltage	30	-30	V
V_{GS}	Gate-to-Source Voltage	±20		V
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$	29	-27
		$T_C = 100^\circ\text{C}$	18	-17
I_{DM}	Pulsed Drain Current ⁽¹⁾	Refer to Fig.4		A
E_{AS}	Single Pulsed Avalanche Energy ⁽²⁾	15	33	mJ
P_D	Power Dissipation	$T_C = 25^\circ\text{C}$	24	24
		$T_C = 100^\circ\text{C}$	10	10
T_J, T_{STG}	Junction & Storage Temperature Range	-55 to 150		°C

Thermal Characteristics

Symbol	Parameter	Max		Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	58	57	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	5.2	5.2	

**Electrical Characteristics-N**($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 30\text{V}$, $V_{GS} = 0\text{V}$	-	-	1.0	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	1.2	1.7	2.2	V
$R_{DS(ON)}$	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10\text{V}$, $I_D = 5\text{A}$	-	15	17	m Ω
		$V_{GS} = 4.5\text{V}$, $I_D = 3\text{A}$	-	21	28	m Ω
Dynamic Characteristics						
R_g	Gate Resistance	$f = 1\text{MHz}$	-	1.8	-	Ω
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}$, $V_{DS} = 15\text{V}$, $f = 1\text{MHz}$	344	481	649	pF
C_{oss}	Output Capacitance		50	71	95	pF
C_{rss}	Reverse Transfer Capacitance		39	54	73	pF
Q_g	Total Gate Charge	$V_{GS} = 0$ to 10V $V_{DS} = 15\text{V}$, $I_D = 5\text{A}$	7	10	14	nC
Q_{gs}	Gate Source Charge		-	1.8	-	nC
Q_{gd}	Gate Drain("Miller") Charge		-	2.1	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-On DelayTime	$V_{GS} = 10\text{V}$, $V_{DD} = 15\text{V}$ $I_D = 5\text{A}$, $R_{GEN} = 2.7\Omega$	-	5	-	ns
t_r	Turn-On Rise Time		-	28	-	ns
$t_{d(off)}$	Turn-Off DelayTime		-	15	-	ns
t_f	Turn-Off Fall Time		-	2	-	ns
Body Diode Characteristics						
I_S	Maximum Continuous Body Diode Forward Current		-	-	29	A
I_{SM}	Maximum Pulsed Body Diode Forward Current		-	-	114	A
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0\text{V}$, $I_S = 5\text{A}$	-		1.2	V
t_{rr}	Body Diode Reverse Recovery Time	$I_F = 5\text{A}$, $di/dt = 100\text{A}/\mu\text{s}$	-	7.7	-	ns
Q_{rr}	Body Diode Reverse Recovery Charge		-	2.3	-	nC

- Notes:
1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
 2. E_{AS} condition: Starting $T_J = 25^\circ\text{C}$, $V_{DD} = 15\text{V}$, $V_{GS} = 10\text{V}$, $R_G = 25\text{ohm}$, $L = 0.5\text{mH}$, $I_{AS} = 7.7\text{A}$, $V_{DD} = 0\text{V}$ during time in avalanche.
 3. $R_{\theta JA}$ is measured with the device mounted on a 1inch^2 pad of 2oz copper FR4 PCB.
 4. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$.



**Electrical Characteristics-P** ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = -250\mu\text{A}$, $V_{GS} = 0\text{V}$	-30	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -30\text{V}$, $V_{GS} = 0\text{V}$	-	-	-1.0	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = -250\mu\text{A}$	-1.2	-1.7	-2.2	V
$R_{DS(ON)}$	Static Drain-Source ON-Resistance ⁽⁵⁾	$V_{GS} = -10\text{V}$, $I_D = -15\text{A}$	-	15	21	$\text{m}\Omega$
		$V_{GS} = -4.5\text{V}$, $I_D = -10\text{A}$	-	20	32	$\text{m}\Omega$
Dynamic Characteristics						
R_g	Gate Resistance	$f = 1\text{MHz}$	-	12	-	Ω
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}$, $V_{DS} = -15\text{V}$, $f = 1\text{MHz}$	921	1290	1741	pF
C_{oss}	Output Capacitance		120	169	228	pF
C_{rss}	Reverse Transfer Capacitance		94	131	177	pF
Q_g	Total Gate Charge	$V_{GS} = 0$ to -4.5V $V_{DS} = -10\text{V}$, $I_D = -3\text{A}$	17	24	32	nC
Q_{gs}	Gate Source Charge		-	4	-	nC
Q_{gd}	Gate Drain("Miller") Charge		-	5	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-On DelayTime	$V_{GS} = -10\text{V}$, $V_{DD} = -15\text{V}$ $I_D = -3\text{A}$, $R_{GEN} = 3\Omega$	-	5	-	ns
t_r	Turn-On Rise Time		-	22	-	ns
$t_{d(off)}$	Turn-Off DelayTime		-	61	-	ns
t_f	Turn-Off Fall Time		-	55	-	ns
Body Diode Characteristics						
I_S	Maximum Continuous Body Diode Forward Current		-	-	-4	A
I_{SM}	Maximum Pulsed Body Diode Forward Current		-	-	-14	A
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0\text{V}$, $I_S = -3\text{A}$	-		-1.2	V
t_{rr}	Body Diode Reverse Recovery Time	$I_F = -20\text{A}$, $di/dt = -100\text{A}/\mu\text{s}$	9	12	17	ns
Q_{rr}	Body Diode Reverse Recovery Charge		-	4.2	-	nC

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
2. E_{AS} condition: Starting $T_J = 25^\circ\text{C}$, $V_{DD} = -15\text{V}$, $V_{GS} = -10\text{V}$, $R_G = 25\text{ohm}$, $L = 0.5\text{mH}$, $I_{AS} = -11.48\text{A}$, $V_{DD} = 0\text{V}$ during time in avalanche.
3. $R_{\theta JA}$ is measured with the device mounted on a minimum recommended pad of 2oz copper FR4 PCB.
4. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$.



Typical Performance Characteristics-N

Figure 1: Power De-rating

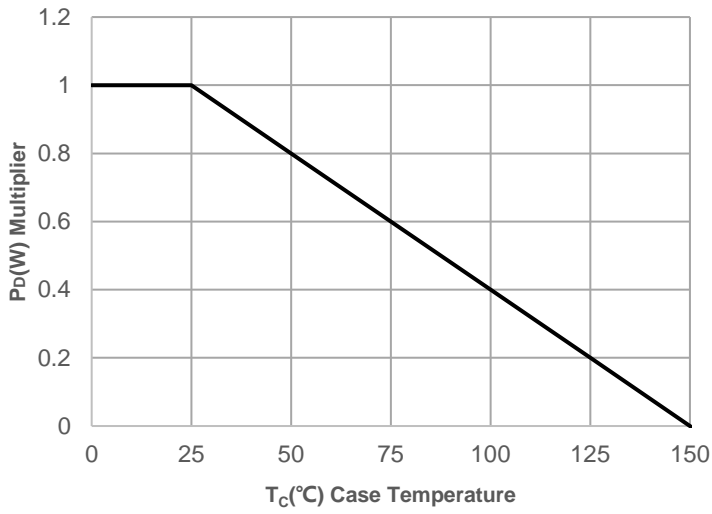


Figure 2: Current De-rating

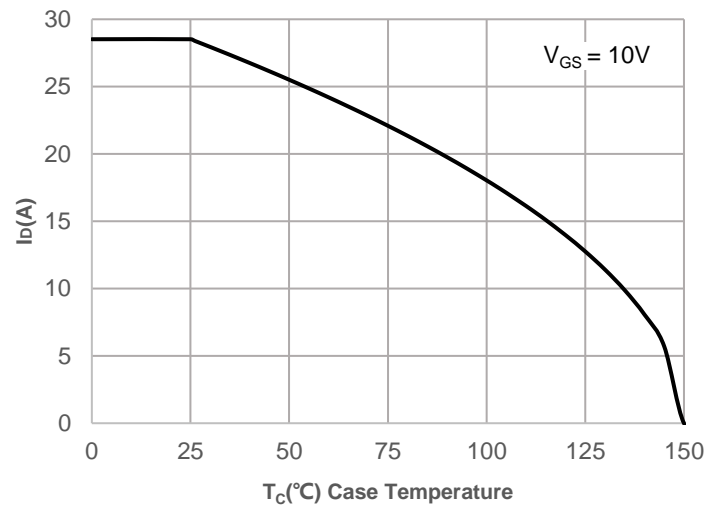


Figure 3: Normalized Maximum Transient Thermal Impedance

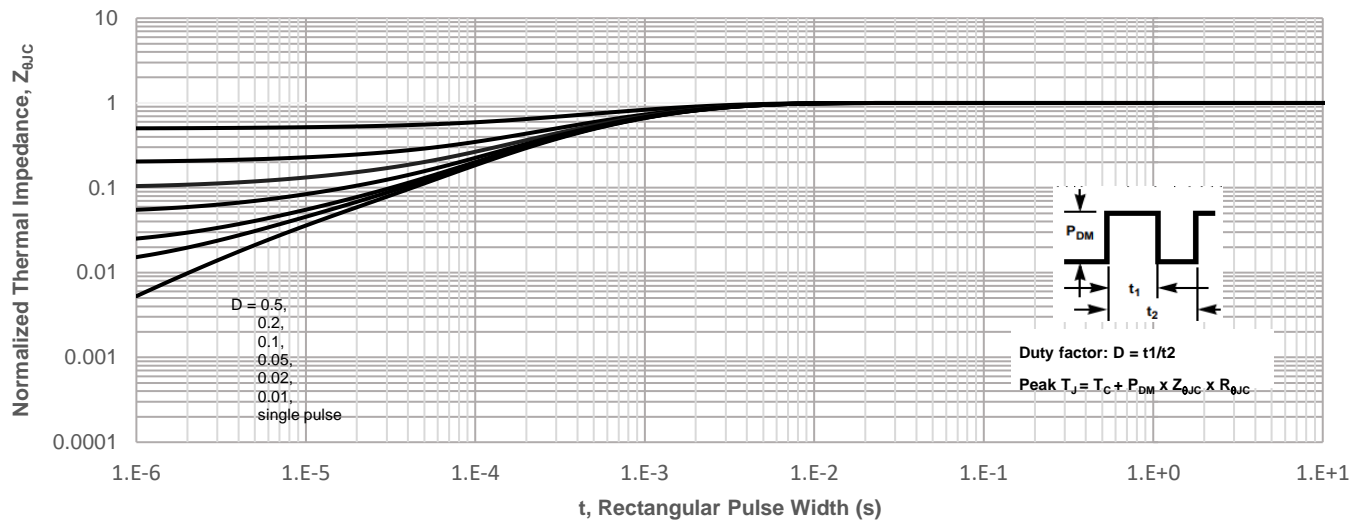


Figure 4: Peak Current Capacity



Typical Performance Characteristics-N

Figure 5: Output Characteristics

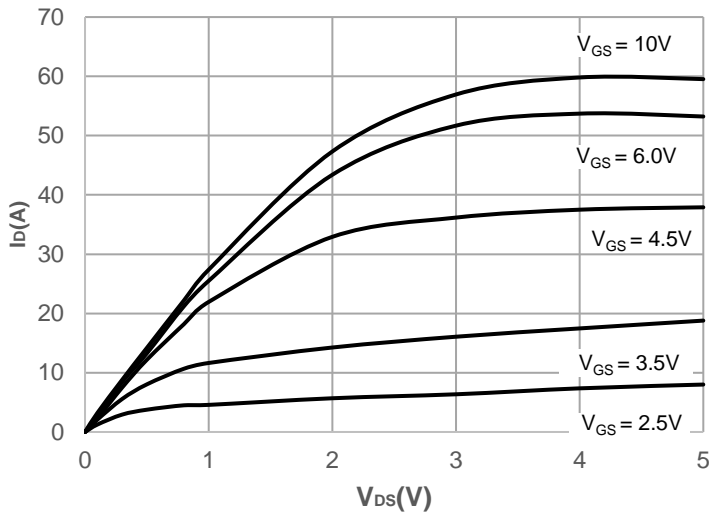


Figure 6: Typical Transfer Characteristics

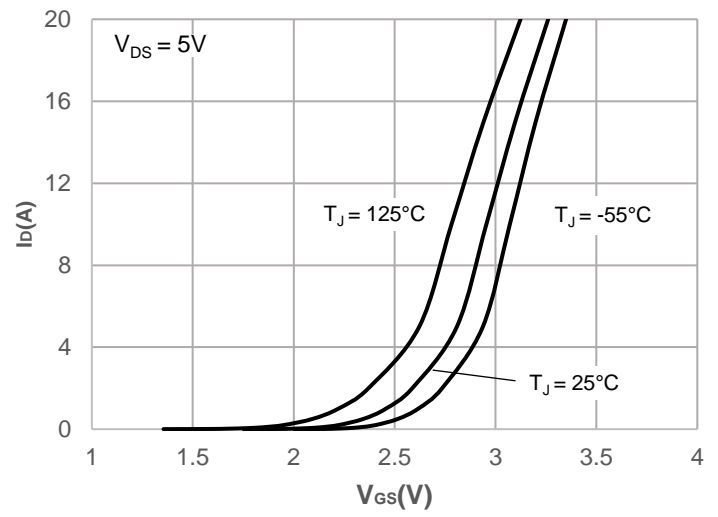


Figure 7: On-resistance vs. Drain Current

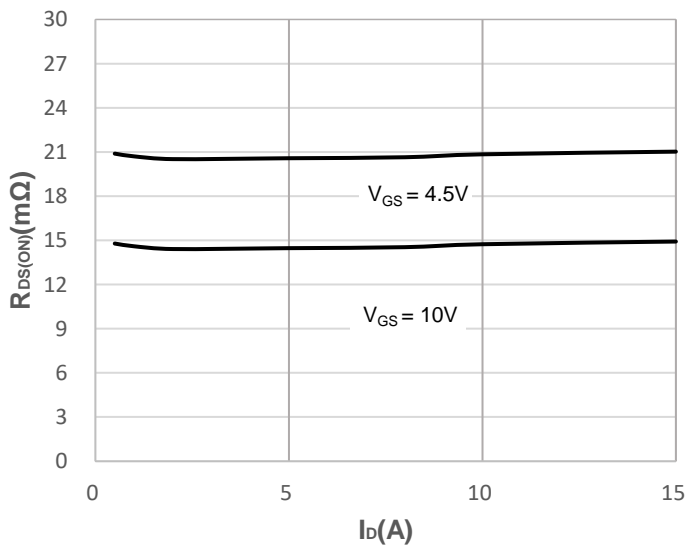


Figure 8: Body Diode Characteristics

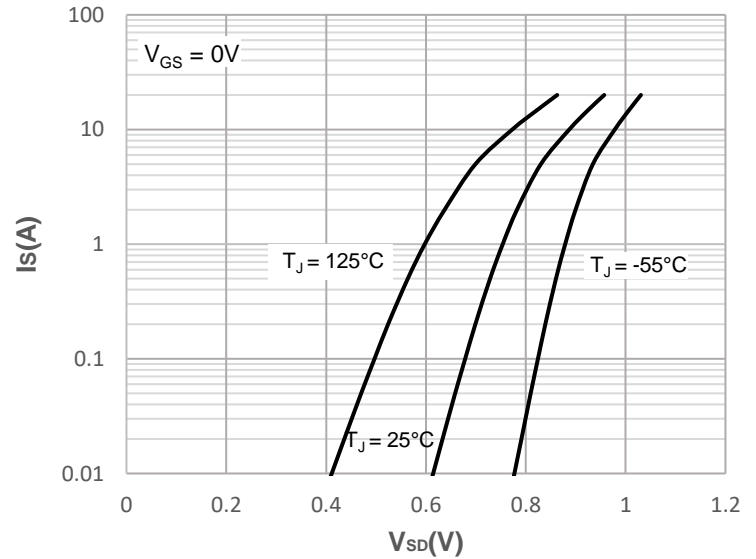


Figure 9: Gate Charge Characteristics

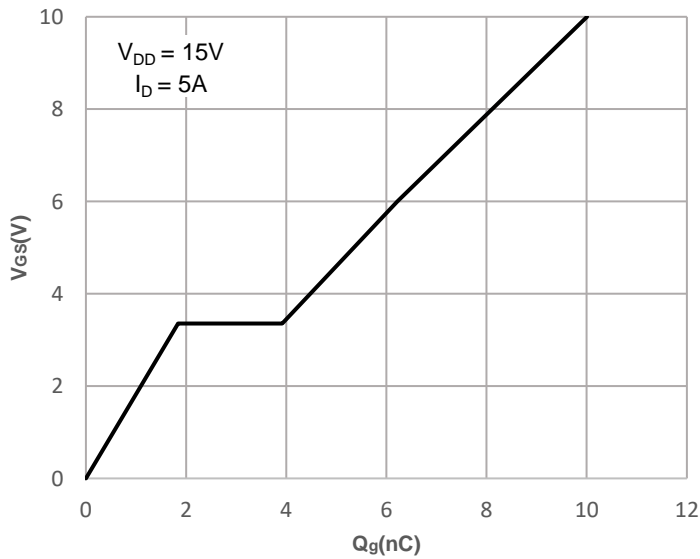
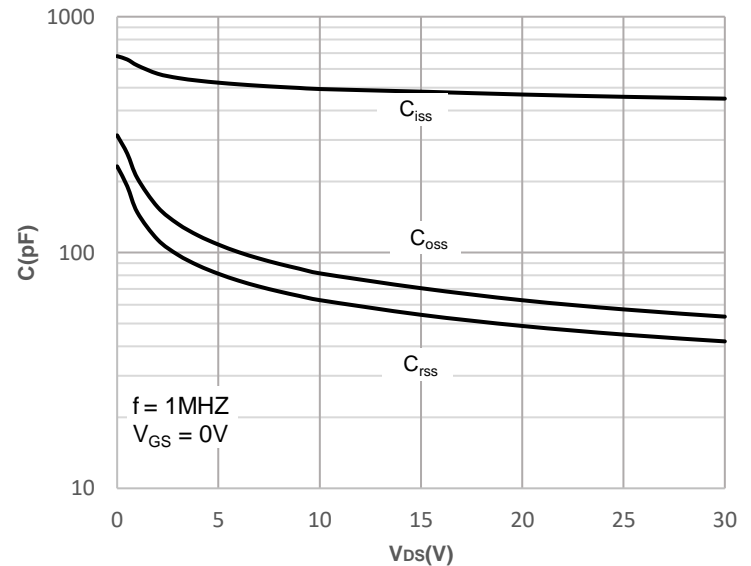


Figure 10: Capacitance Characteristics



Typical Performance Characteristics-N

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

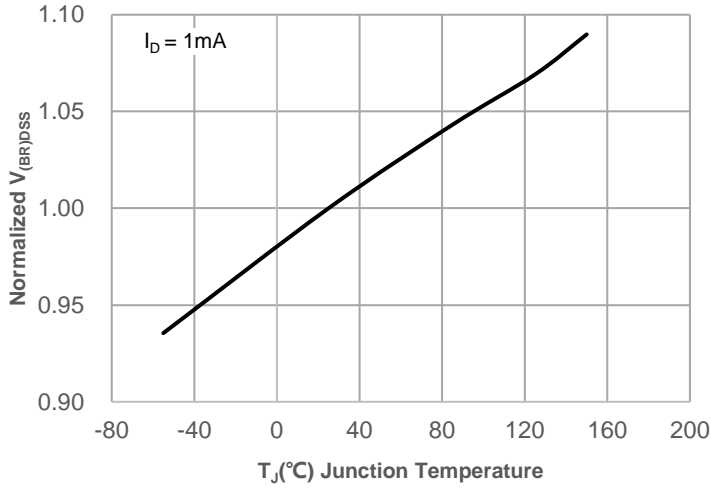


Figure 12: Normalized on Resistance vs. Junction Temperature

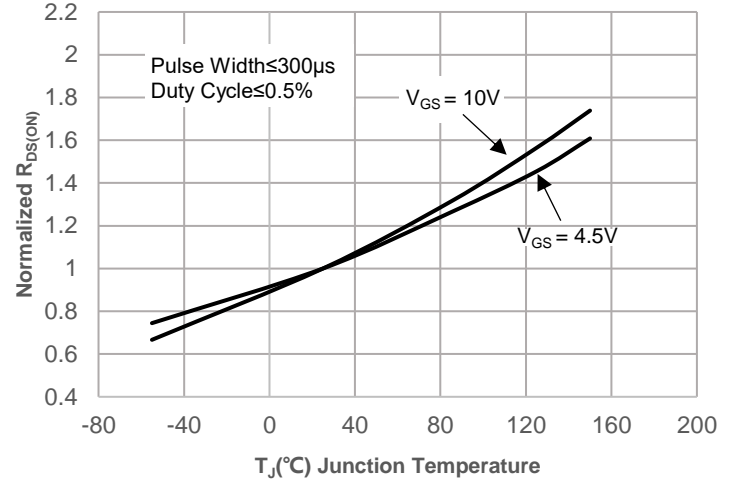


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

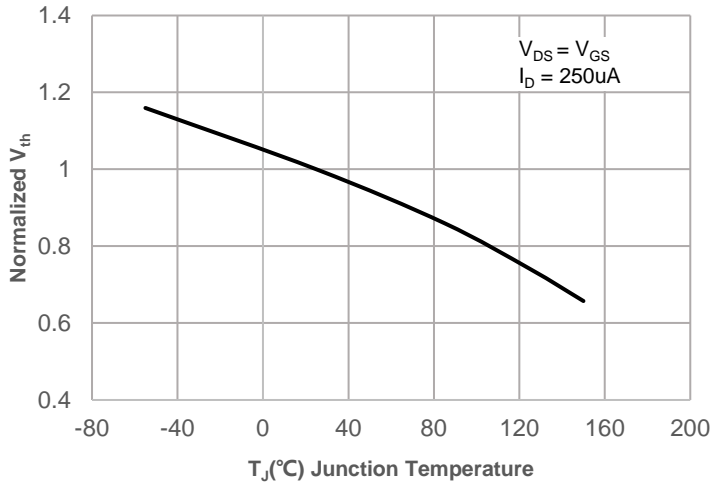


Figure 14: RDS(ON) vs. VGS

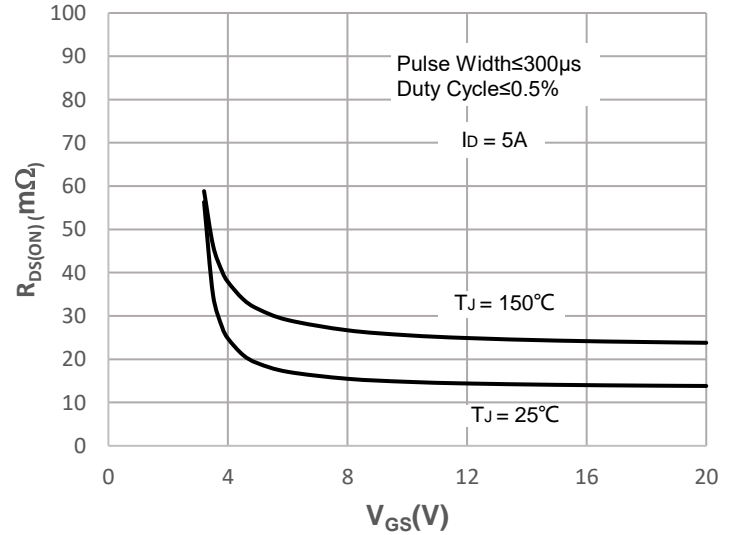
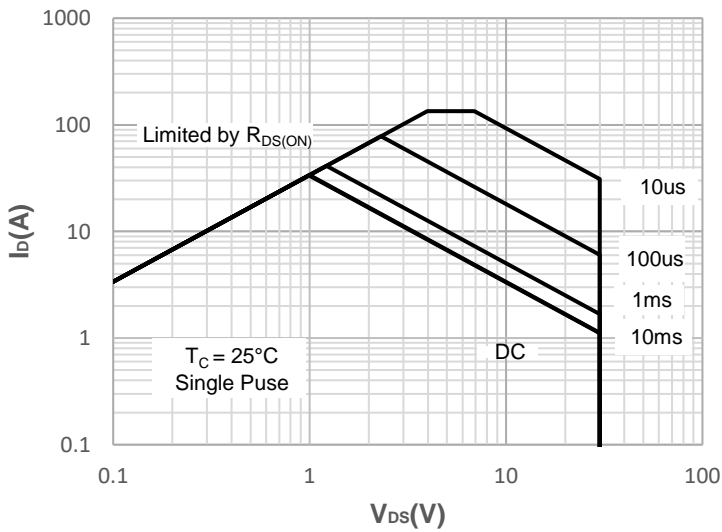


Figure 15: Maximum Safe Operating Area



Typical Performance Characteristics-P

Figure 1: Power De-rating

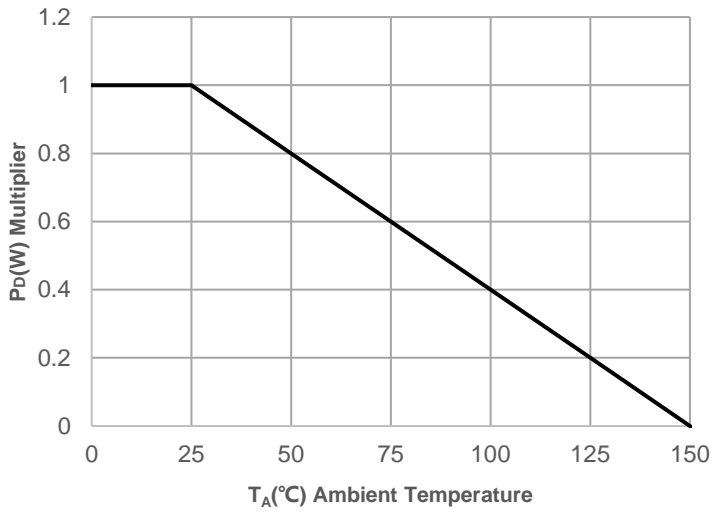


Figure 2: Current De-rating

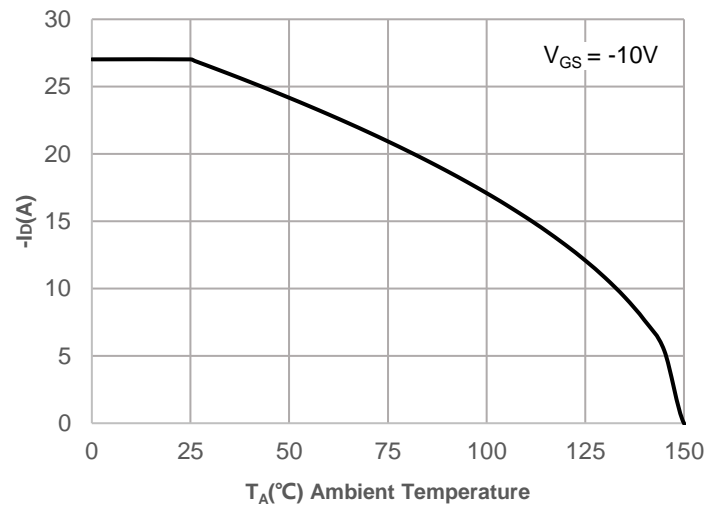


Figure 3: Normalized Maximum Transient Thermal Impedance

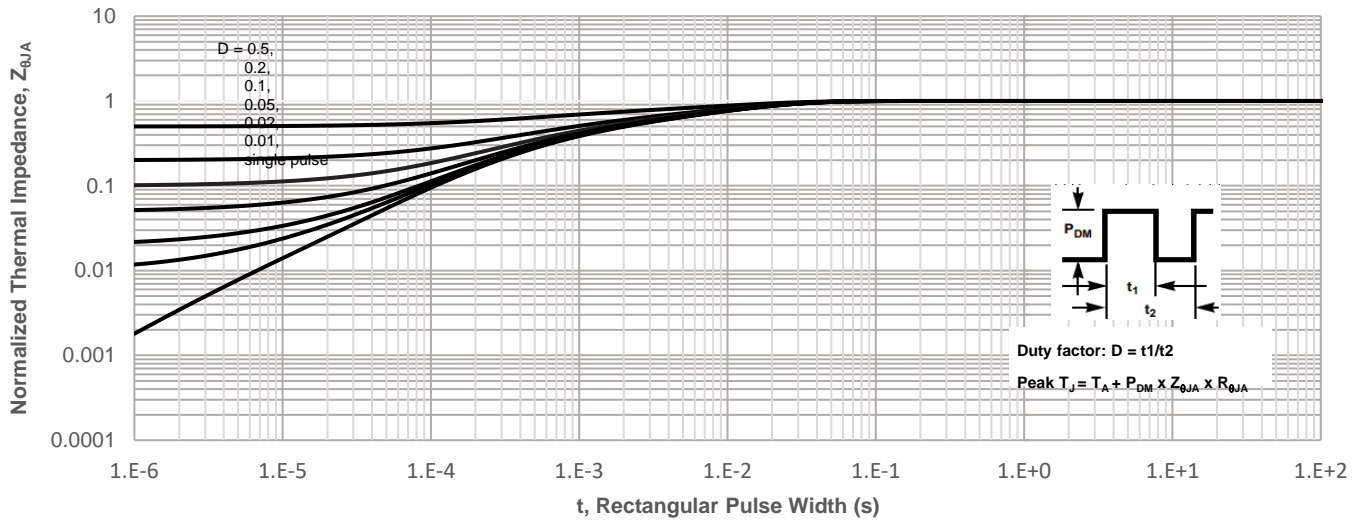


Figure 4: Peak Current Capacity



Typical Performance Characteristics-P

Figure 5: Output Characteristics

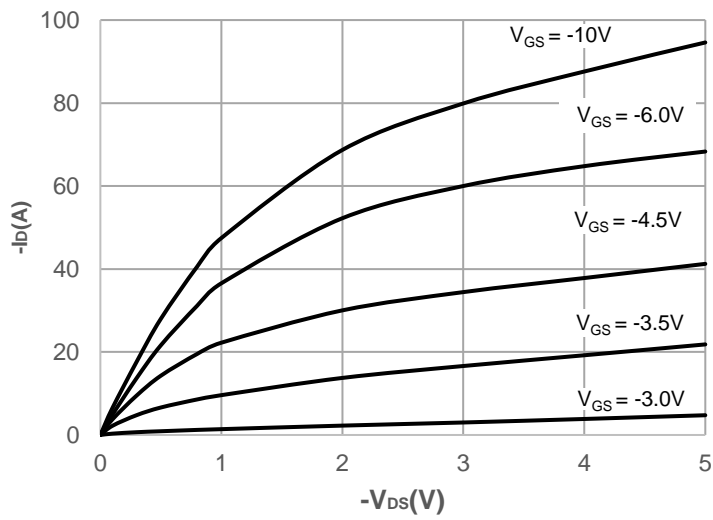


Figure 6: Typical Transfer Characteristics

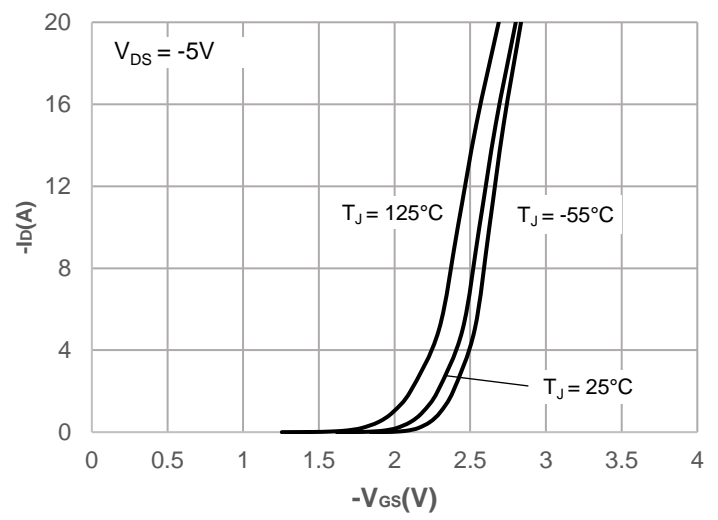


Figure 7: On-resistance vs. Drain Current

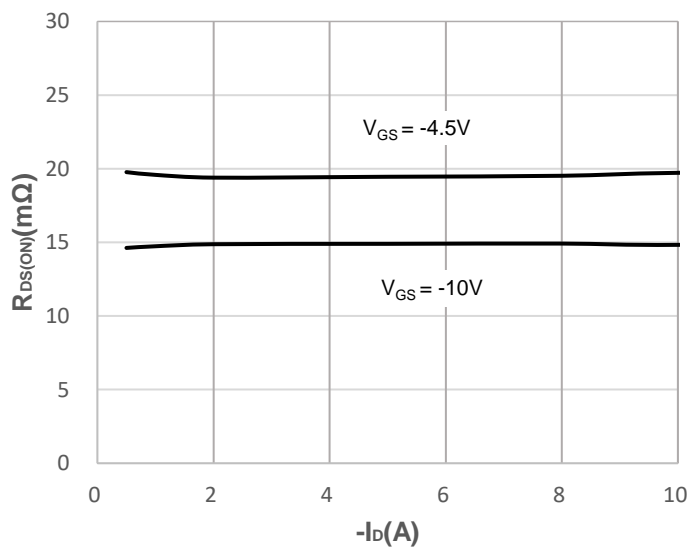


Figure 8: Body Diode Characteristics

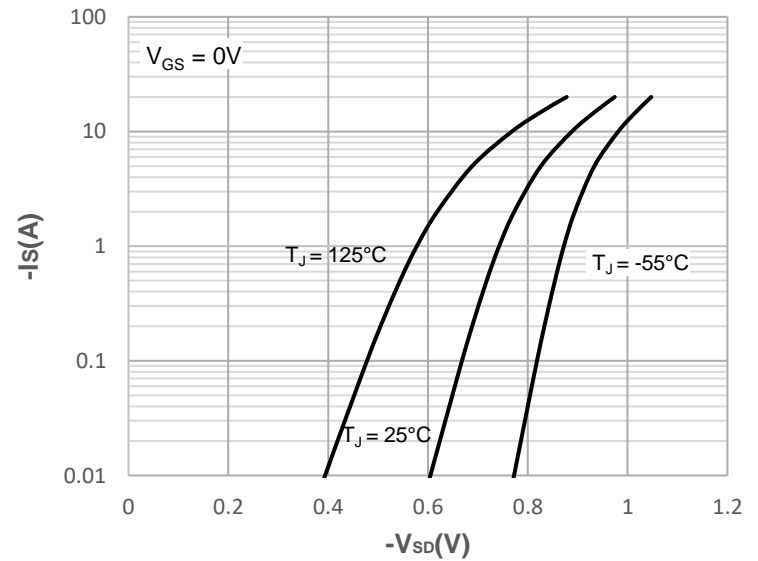


Figure 9: Gate Charge Characteristics

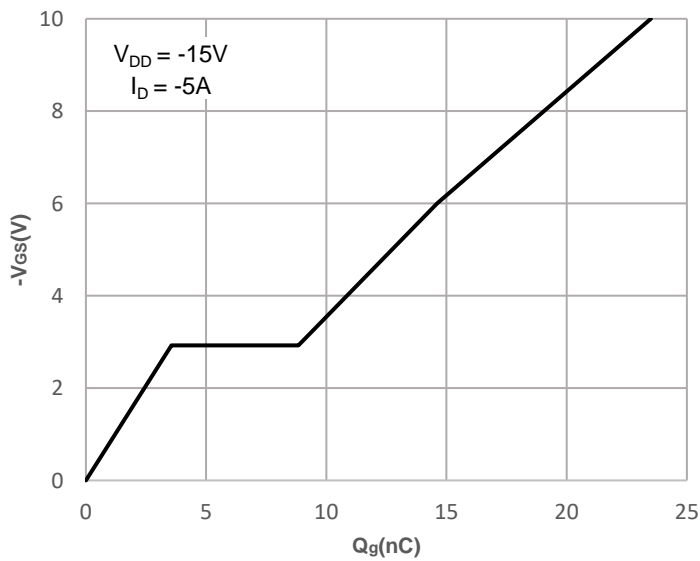
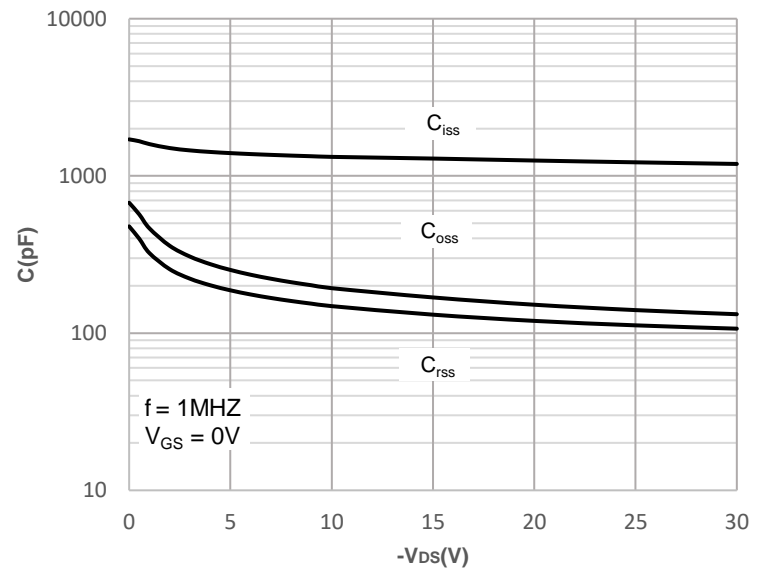


Figure 10: Capacitance Characteristics



Typical Performance Characteristics-P

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

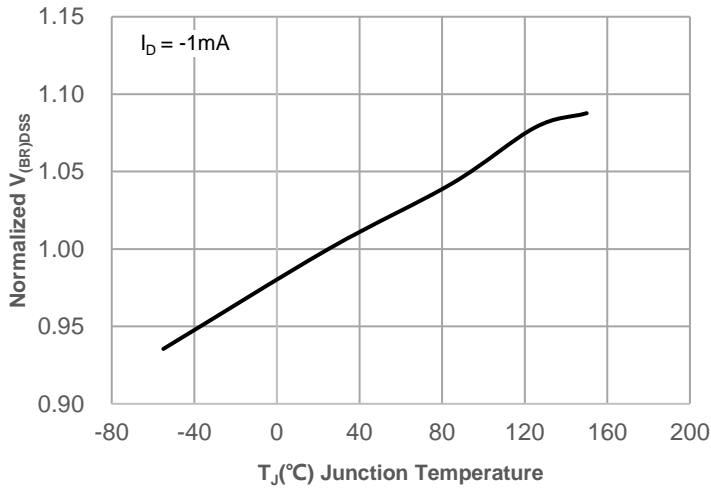


Figure 12: Normalized on Resistance vs. Junction Temperature

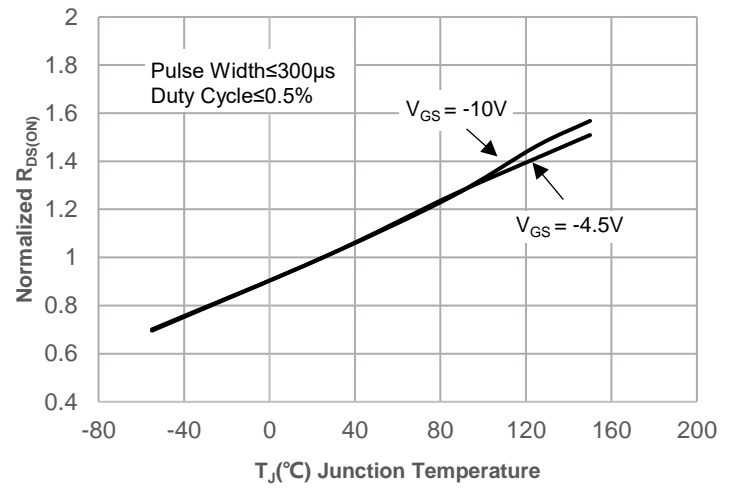


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

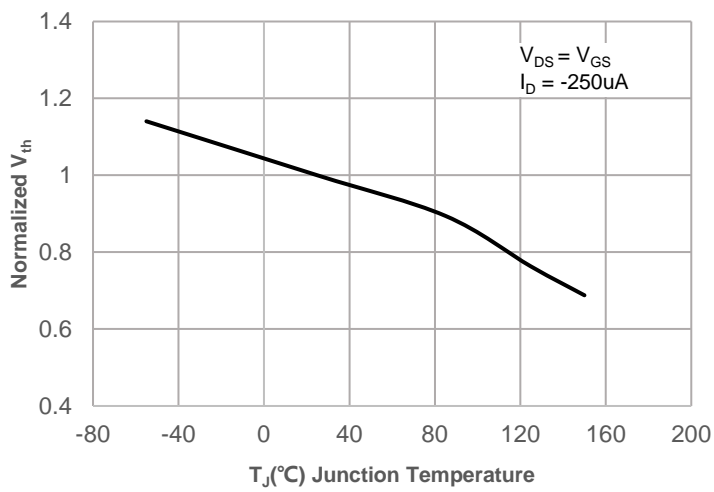


Figure 14: R_DS(ON) vs. V_GS

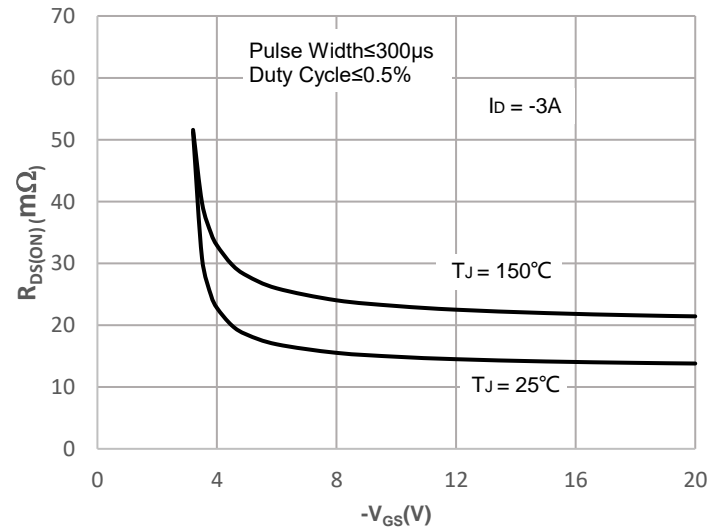
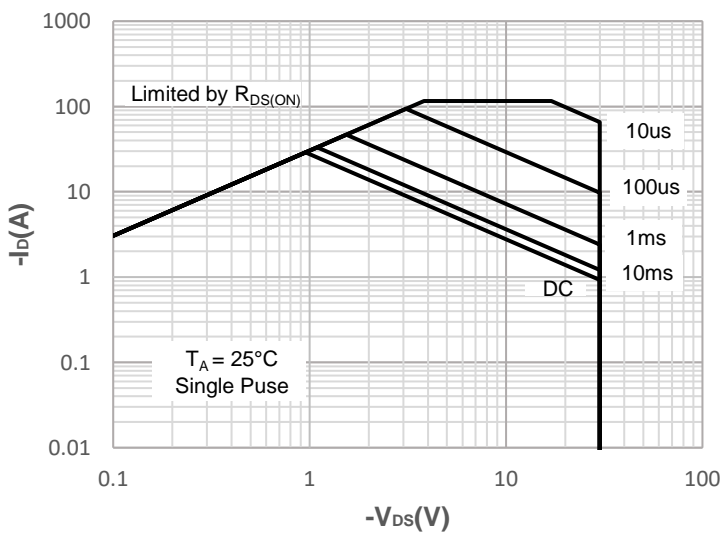
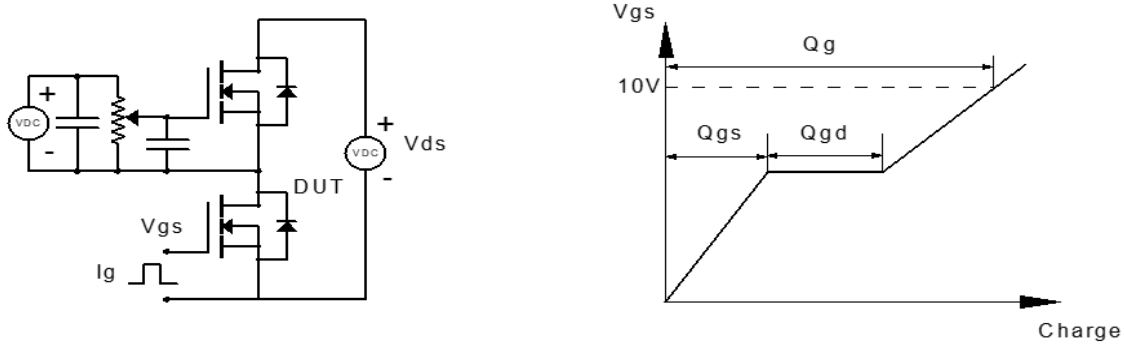
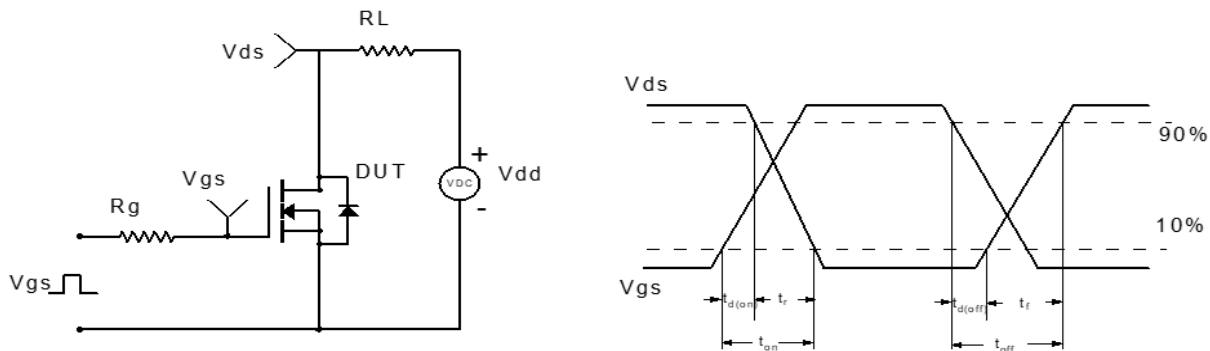
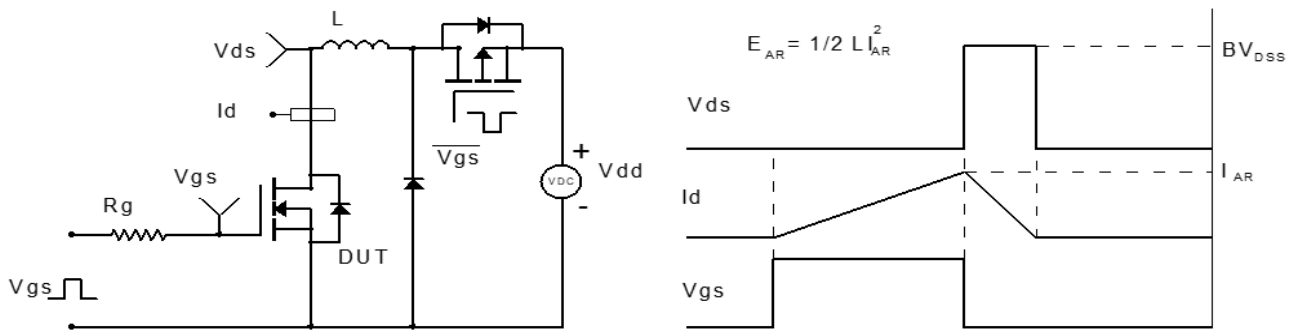
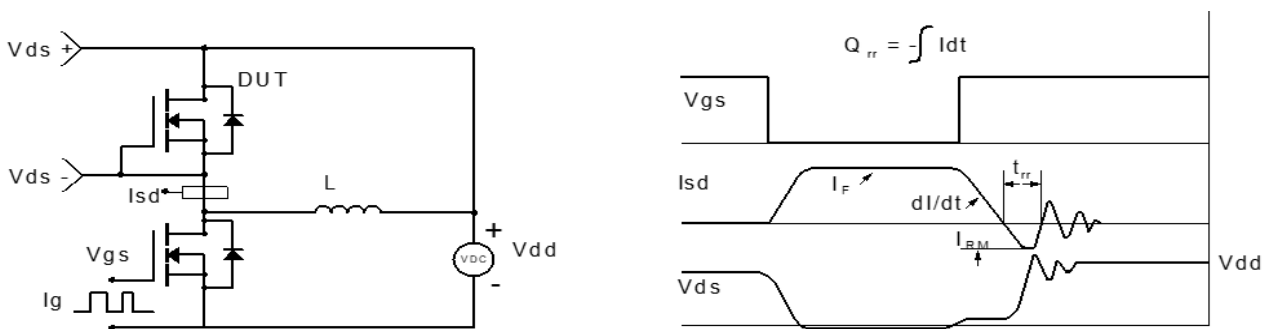


Figure 15: Maximum Safe Operating Area



Test Circuit

Figure 1: Gate Charge Test Circuit & Waveform

Figure 2: Resistive Switching Test Circuit & Waveform

Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

Figure 4: Diode Recovery Test Circuit & Waveform

Test Circuit

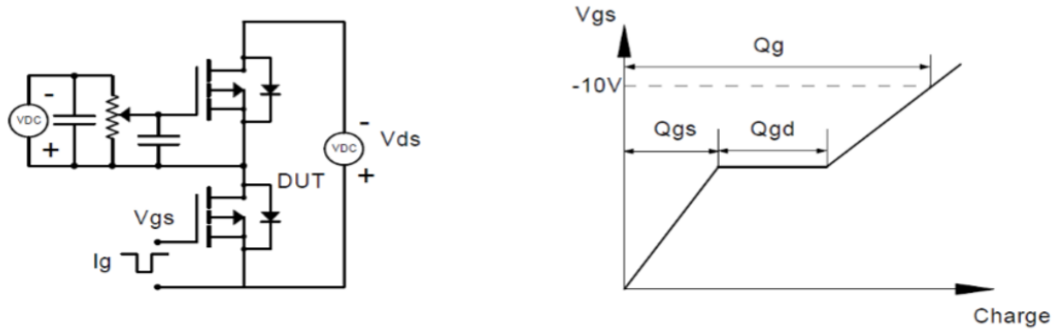


Figure 1: Gate Charge Test Circuit & Waveform

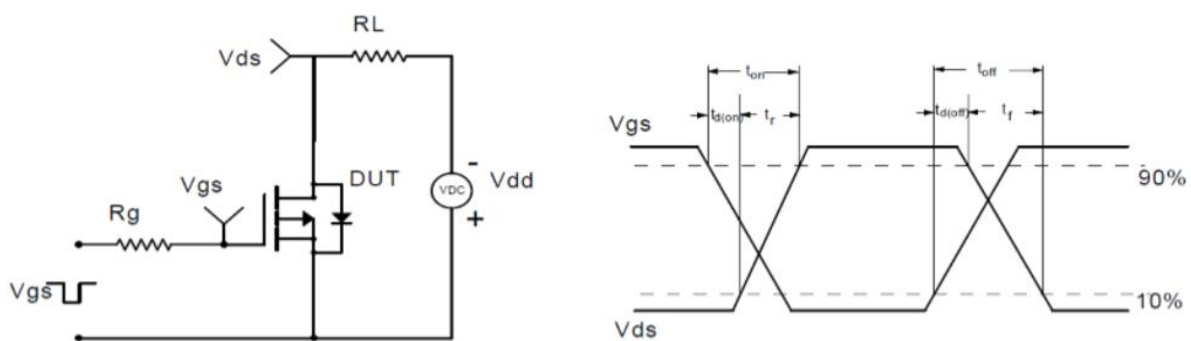


Figure 2: Resistive Switching Test Circuit & Waveform

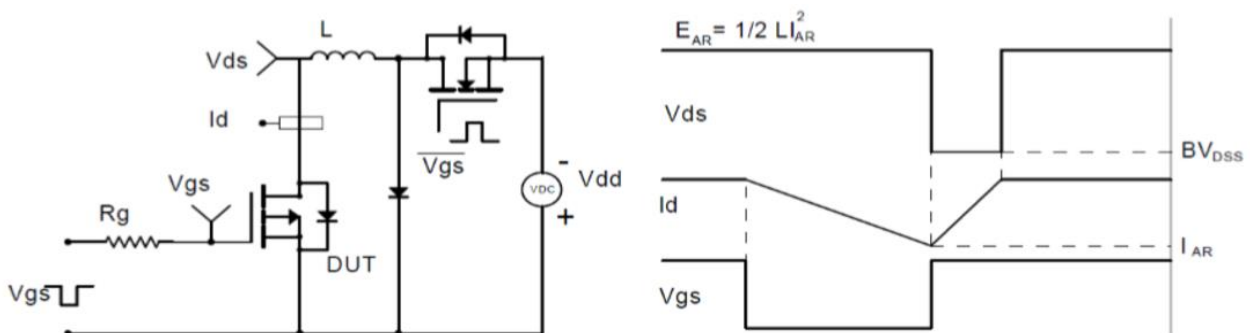


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

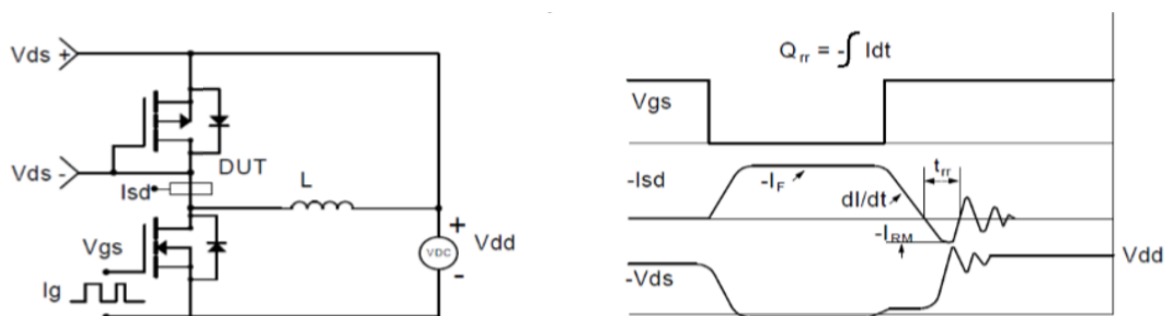
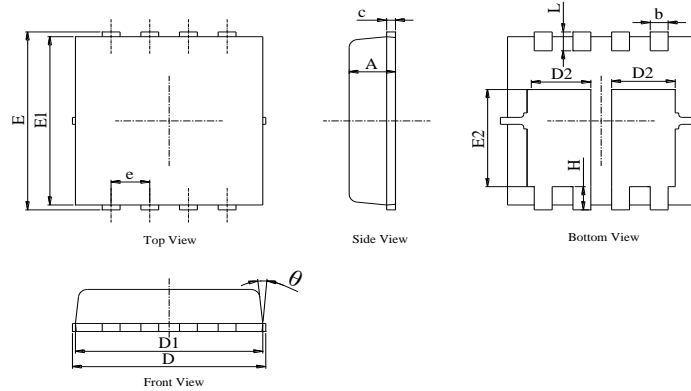


Figure 4: Diode Recovery Test Circuit & Waveform



Package Mechanical Data(PDFN5X6-8L-D)

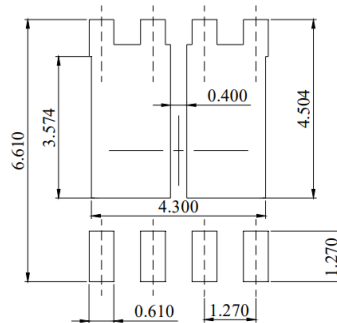
Package Outline



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M,1994.
 2. ALL DIMENSIONS IN MILLIMETER (ANGLE IN DEGREE).
 3. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

DIM	MILLMETER		
	MIN.	NOM.	MAX.
A	0.90	1.00	1.15
A1	0.00	-	0.10
b	0.31	0.41	0.51
b1	0.15	0.25	0.35
c	0.24	0.32	0.40
D1M	4.95	5.05	5.15
D1	4.00	4.10	4.20
D2	0.50	0.60	0.70
E	6.05	6.15	6.25
E1	5.50	5.60	5.70
E2	3.31	3.41	3.51
e	1.27BSC		
H	0.60	0.70	0.80
L	0.50	0.70	0.80
L1	-	-	0.13
a	-	-	12°

Recommended Soldering Footprint



DIMENSIONS:MILLIMETERS

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